

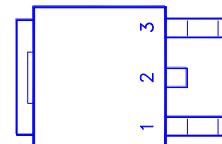
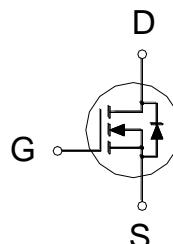
NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****P5515BD**

TO-252

Halogen-Free & Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
150V	55mΩ	24.6A



1. GATE
2. DRAIN
3. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	150	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	24.6	A
	$T_C = 100^\circ\text{C}$		15.5	
Pulsed Drain Current ¹		I_{DM}	60	A
Avalanche Current		I_{AS}	11.6	
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	67.9	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	83	W
	$T_C = 100^\circ\text{C}$		33	
Junction & Storage Temperature Range		T_J, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		1.5	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	150			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	1.9	2.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 120\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 100\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	

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Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 10A$		43	65	$m\Omega$
		$V_{GS} = 10V, I_D = 15A$		42	55	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 10A$		76		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	1639	2049	2458	pF
Output Capacitance	C_{oss}		147	184	220	
Reverse Transfer Capacitance	C_{rss}		48	81	113	
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	0.5	1	1.5	Ω
Total Gate Charge ²	Q_g	$V_{GS} = 10V, V_{DS} = 75V, I_D = 15A$	32	41	49	nC
Gate-Source Charge ²	Q_{gs}		5.1	6.4	7.7	
Gate-Drain Charge ²	Q_{gd}		6.5	10.9	15.3	
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DS} = 75V$ $I_D \geq 15A, V_{GS} = 10V, R_{GEN} = 6\Omega$		17		nS
Rise Time ²	t_r			18		
Turn-Off Delay Time ²	$t_{d(off)}$			68		
Fall Time ²	t_f			45		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S				24.6	A
Forward Voltage ¹	V_{SD}	$I_F = 15A, V_{GS} = 0V$			1	V
Reverse Recovery Time	t_{rr}	$I_F = 15A, dI_F/dt = 100A/\mu S$	30	60	90	nS
Reverse Recovery Charge	Q_{rr}		59	118	177	nC

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

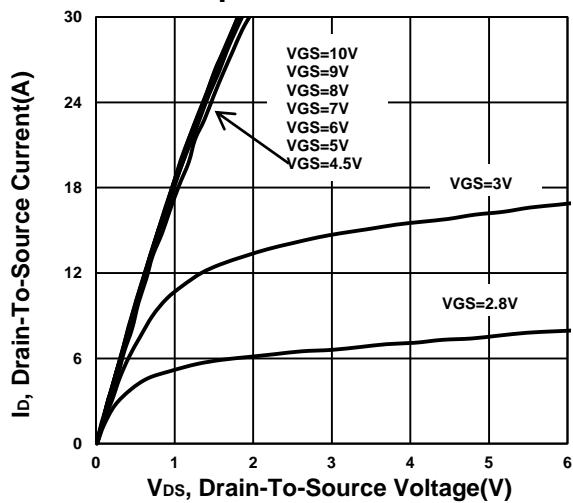
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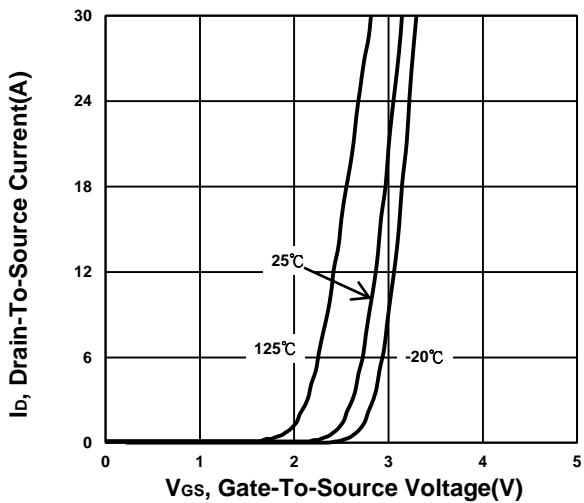
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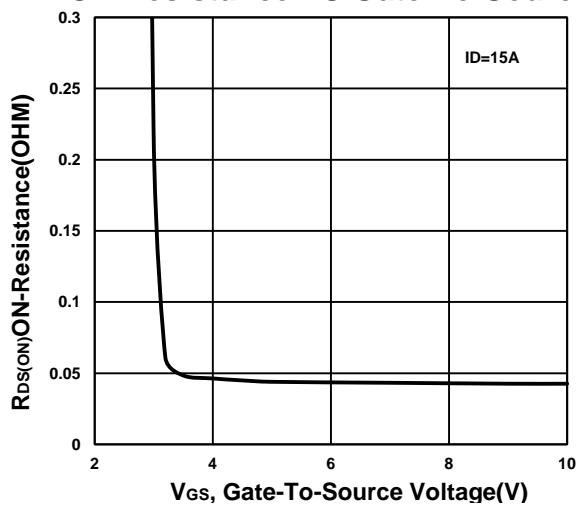
Output Characteristics



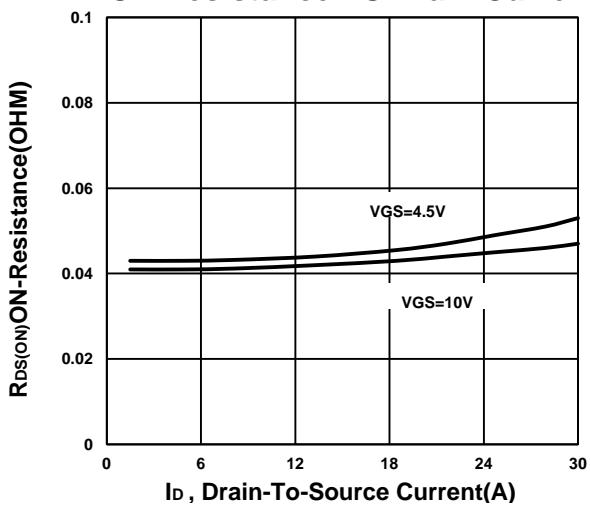
Transfer Characteristics



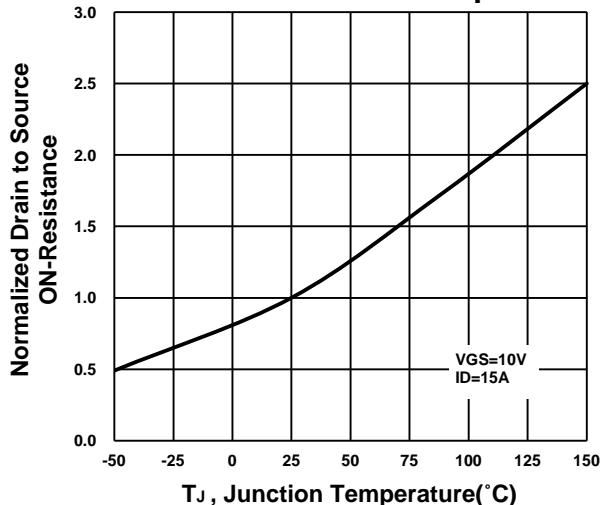
On-Resistance VS Gate-To-Source



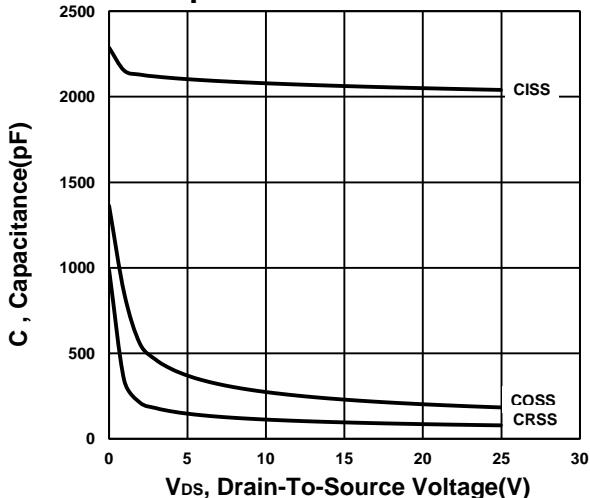
On-Resistance VS Drain Current



On-Resistance VS Temperature



Capacitance Characteristic



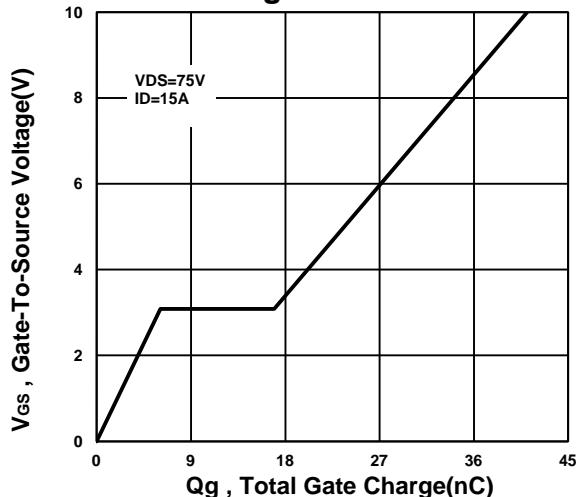
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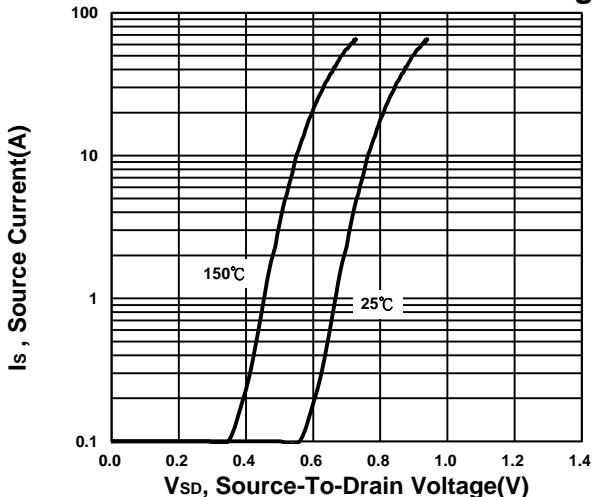
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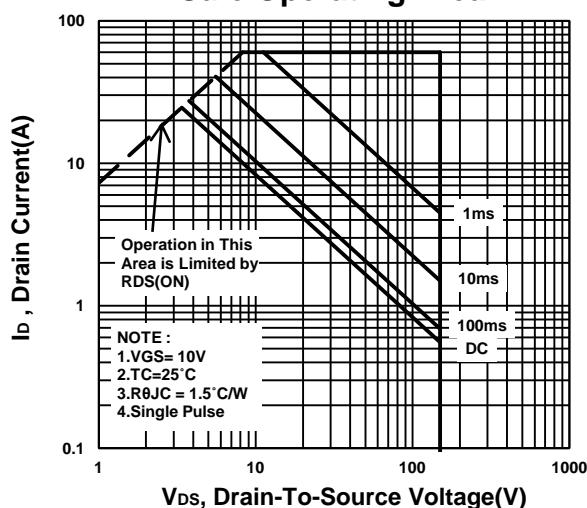
Gate charge Characteristics



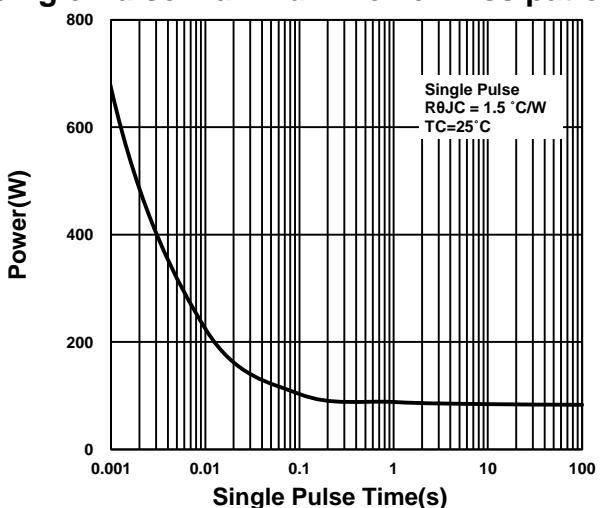
Source-Drain Diode Forward Voltage



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

